is slow compared to the rate of polymerization. Thus, although the thermodynamically stable state under the con-ditions indicated appears to be 0.004% SiO₂ as monomer, the rate of polymerization is so fast as compared with the rate of depolymerization that polymerization to higher intermediate polymers takes place before the stable state is reached

The Effect of Catalysts on Polymerization of Monosilicic Acid.-Experiments studying the effect of catalysts confirm results reported by Iler² regarding fluoride. Thus, the most active catalyst found was the fluoride ion, which, when added to the extent of one or two parts per million, doubles the rate of polymerization of silicic acid at pH 2.9 and 1.90° This effect of fluoride ion is counteracted by the addition of 10 parts per million of aluminum ions, presumably due to the formation of the complex fluoaluminate ion.

The action of a wide variety of inorganic and organic compounds was investigated, but none of the materials investigated had a very profound effect, in the *p*H range of 2-3. Specifically, molybdic acid at 0.001 M or mannite at 10% increased the rate of polymerization slightly, but nickel sulfate, ferrous sulfate, silver nitrate, copper sulfate,

at 0.00006 M, aluminum sulfate or phosphoric acid at 0.001 *M*, or sodium thiocyanate, potassium bromide, beryl-lium sulfate, boric acid, stannic chloride, titanium sulfate, at 0.02 *M*, had no effect. The addition of 10% methyl alcohol caused a slight decrease in the polymerization rate.

Strength of Silicic Acids .- It was found that monosilicic and polysilicic acids are very weak acids, since they apparently do not contribute any appreciable hydrogen ion concentration to their solutions. Thus, when a solution of 0.1 M silicic acid was prepared in a solution of dilute H₂SO₄ of pH 2.10, the pH of the resulting silicic acid solution (after complete removal of Na⁺ by ion exchange) was 2.10. Moreover, when a monomer solution was prepared at pH 2 and then adjusted to pH 3.89 by the addition of a trace of sodium metasilicate, it was found that, in spite of the fact that the degree of polymerization increased from 1.34 to over 5, the pH remained constant. These observations agree with the values of dissociation constants of orthosilicic acid reported to be $10^{-9.8}$ and $10^{-12.16.7}$

(7) P. S. Roller and Guy Ervin, Jr., THIS JOURNAL, 62, 461 (1940). WILMINGTON 98. DEL.

[CONTRIBUTION FROM THE DEPARTMENT OF CHEMISTRY AND THE PURDUE RESEARCH FOUNDATION, PURDUE UNIVERSITY]

An Electron Diffraction Investigation of the Molecular Structure of Hexafluoroethane¹

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The interatomic distances in hexafluoroethane have been determined by electron diffraction using the visual correlation occdure. The following results were obtained: $C-F = 1.330 \pm 0.015$ Å., $C-C = 1.51 \pm 0.06$ Å., and $\angle FCF = 108 \pm 1.5^{\circ}$. procedure. The results are compared with two earlier electron diffraction investigations.

A previous electron diffraction investigation² of the structure of hexafluoroethane gave $\bar{C}-C$ = 1.45 ± 0.06 Å., C-F = 1.35 ± 0.02 Å., and \angle FCF = 107.5 $\pm 1.5^{\circ}$. Even with the rather large uncertainty on the C-C bond distance, these results indicated that this distance is considerably shorter than the value of 1.535 Å. found in ethane.³ A second electron diffraction investigation² did not confirm this unusually short C–C bond but gave the following results: C–C = 1.52-1.60 Å., C–F = 1.37-1.34 Å., and \angle FCF = $107.5-109.5^{\circ}$.

The large discrepancy between these results suggested the present investigation of the structure of hexafluoroethane. It seemed that the earlier work might be improved upon in two ways: first, by obtaining diffraction patterns extending to larger scattering angles and, second, by a careful consideration of the vibrational and rotational effects within the molecule. These latter effects have often been neglected in electron diffraction studies.

Experimental

The sample of hexafluoroethane (b.p. -76.2°) was sup-The sample of nexatiuoroethane (b.p. -76.2°) was supplied by the Central Research Department of the Minnesota Mining and Manufacturing Company; infrared spectroscopy indicated the sample to be better than 99% pure. Electron diffraction photographs were prepared in the customary manner⁴ using an apparatus built by Dr. H. J. Yearian of the Purdue Physics Department. The camera distance was about 10.7 cm. and the wave length of the electron beam, as determined from transmission pattern of ZnO, was about 0.055 Å. The recorded diffraction pattern for hexafluoroethane extended to a q value of about 105.

Interpretation of the Pattern

The visual correlation method^{4,5} and the radial distribution method^{6,7} were used in the interpretation of the recorded pattern. The radial distribution function was calculated from the equation⁷

$$rD(r) = \sum_{q=1,2}^{q\max} I(q) \exp\left(-bq^2\right) \sin\left(\frac{\pi qr}{10}\right) \qquad (1)$$

by the use of punched cards.⁷ I(q) is the visual intensity curve (curve vis., Fig. 2) which is drawn assuming no falling off of intensity with increasing q. The constant b was chosen so that $\exp(-bq^2) = 0.10$ at q = 105. The terms for the range q = 1to q = 20 were obtained from one of the acceptable theoretical intensity curves which were calculated on I.B.M. machines, using the equation⁷

$$I(q) = \sum_{i} \sum_{j} \frac{Z_i Z_j}{r_{ij}} \exp\left(-b_{ij} q_2\right) \sin\left(\frac{\pi q}{10} r_{ij}\right) \quad (2)$$

All measurements and intensity estimates were made by three independent observers. The averages of the measurements of the three observers led to the q_0 values which are given in Table I.

Theoretical intensity curves were calculated over much of the parameter field indicated in Fig. 1 for rigid models of hexafluoroethane in which the symmetry of the point group D_{3d} was assumed. Curve

⁽¹⁾ Contains material from the Ph.D. thesis of James L. Brandt, Purdue Research Foundation Fellow in Chemistry, 1951-1952.

⁽²⁾ A survey of electron diffraction results through 1949 is found in the tabulation by P. W. Allen and L. E. Sutton, Acta Cryst., 8, 46 (1950).

⁽³⁾ This value is quite accurate and is based on a combination of electron diffraction and infrared spectroscopic data made by K. Hedberg and V. Schomaker, THIS JOURNAL, 73, 1482 (1951).

⁽⁴⁾ L. O. Brockway, Revs. Modern Phys., 8, 231 (1936).

⁽⁵⁾ L. Pauling and L. O. Brockway, J. Chem. Phys., 2, 867 (1934).
(6) L. Pauling and L. O. Brockway, THIS JOURNAL, 57, 2684 (1935).

⁽⁷⁾ P. A. Shaffer, V. Schomaker and L. Pauling, J. Chem. Phys., 14, 659 (1946).

		q/q_9 Values of Acceptable Models for Hexafluoroethane									
Fea Max	ture Min		Р	R	s	x	Y	Z	cc	DD	
1		19 45	(0.961)	(0, 951)	(0.941)	(0.987)	(0.967)	(0.967)	(0.998)	(0.998)	
1	2	26 46	971	954	939	. 996	.981	.968	1.005	1.002	
2	2	30.12	990	976	.965	1.013	1.005	.988	1.023	1.021	
-	3	33 01	979	951	.956	0.997	0.991	.979	1.012	1.003	
3	0	37 79	961	.946	.941	.986	.973	.966	0.996	0.990	
	4	43 10	963	969	.940	.987	.977	, 963	1.010	.992	
4	-	47 77	(970)	(.957)	(.945)	(1.000)	(.984)	(.971)	(1.013)	(.994)	
-	5	55 73	(976)	(.965)	(,956)	(1,002)	(.994)	(.984)	(1.020)	(1.014)	
5	U	59 40	983	970	.964	1.007	1.000	.989	1.020	1.012	
Ū	6	62.91	976	.960	.942	0.997	0.981	.966	1.007	0.994	
6	Ŭ	66.96	(.993)	(.956)	(,931)	(1.012)	(.993)	(.963)	(1.023)	(1.008)	
Ŭ	7	72.81	979	.966	,948	1.000	.989	.975	1.014	1.003	
7	•	77 46	.984	.969	.949	1.009	.991	.975	1.028	1.002	
•	8	82.61	.990	.978	.972	1.012	1.003	.995	1.026	1.016	
8	-	86 69	982	972	.962	1.004	0.994	.981	1.016	1.007	
0	9	90.62	.976	.965	.953	1.000	.988	.975	1.013	0.999	
9	Ũ	94.86	.985	.948	.956	1.005	.995	.980	1.014	1.004	
· ·	10	99 75	.988	.977	,965	1.012	1.001	.988	1.024	1.011	
10	10	104.15	.986	.975	.963	1.010	0.999	.986	1.020	1.012	
Av.	(15 fe	atures)	0,980	0.965	0.954	1.002	0.991	0.978	1.015	1.005	
Mean dev.		<i>.</i>	± 0.007	± 0.009	± 0.009	± 0.007	± 0.008	± 0.008	± 0.007	± 0.007	
			ZECE	•				Å.			
		105	107눈	- 109½	111+	-۴		2 3			

TABLE I



Fig. 1.--Parameters of models for which intensity curves were calculated. The dotted line indicates the limits of uncertainty in choosing the final model.

A of Fig. 2 represents the best of the rigid models and it may be rejected because of the well-resolved maximum rather than a shelf on the outer portion of the fourth maximum and because of the presence of a shelf on the inner portion of the ninth maxi-The parameters for Model A were C-C =mum. 1.54 Å., C-F = 1.34 Å., and \angle FCF = 109.5°.

The failure of all rigid models to produce a suitable theoretical intensity curve indicated the importance of taking into account the intramolecular motions of the atoms. The problem of the effect of restricted internal rotation on the electron diffraction pattern has been discussed by Karle.⁸ Adoption of Karle's expressions for use with the I.B.M. punched card method⁷ permitted calculations for models corresponding to different potential barriers hindering the rotation of one CF₃ group with respect to the other. Models were then calculated for the parameters shown in Fig. 1 using a potential barrier of 5.0 kcal./mole; a description of agreement of the curves for these models follows.

Curves S and Z are shown in Fig. 2 as representa-

(8) J. Karle, J. Chem. Phys., 15, 202 (1947).



Fig. 2.-Radial distribution and intensity curves.

tive of the entirely acceptable models which are enclosed by the dotted lines in Fig. 1. The area of acceptability indicates that the \angle FCF is about 108°.

Models with an \angle FCF of 105.5 or 106.5° such as E or K, give rise to curves which disagree completely with the visual curve in the shape of the sixth maximum. In addition, the relative depths of the ninth and tenth minima are wrong in the curves for these models. Curves corresponding to models with an \angle FCF of 110.5 or 111.5° are completely incompatible with the visual curve as seen by curve LL or by a curve intermediate between EE and LL.

Curves for models which lie above or on the dotted line in Fig. 1 were rejected or considered borderline for the following reasons: curve P, which is borderline at best, shows the fourth peak as an unresolved doublet rather than a peak with a shoulder on its outer portion; curves N and O are worse in this respect. Curve X is similar to P and is thus accepted as a borderline fit while W and BB are rejected for the same reasons as N and O. Models CC and DD are better as regards the fourth maximum but are considered borderline fits because the sixth maximum is too intense relative to the fifth.

Curves T, AA and EE, corresponding to models below the acceptable area in Fig. 1, are rejected largely on the basis of the appearance of the sixth and seventh maxima.

Table I summarizes the q_{calc}/q_{obs} values for the acceptable or borderline models. The ratios for certain features are enclosed in parentheses; these were thought to be unreliable and were not used in calculating the q/q_0 averages.

The effects of different potential barriers are illustrated in Fig. 3 where curves Y_3 , Y_5 and Y_7 correspond to model Y of Fig. 1 with potential barriers of 3.0, 5.0 and 7.0 kcal./mole, respectively. It is noted that as the barrier hindering free rotation is increased, *i.e.*, as the molecule is made more rigid, the shelf on the outer portion of maximum four becomes more pronounced and the intensity of the sixth maximum increases relative to the fifth



Fig. 3.—Theoretical intensity curves showing the effect of various barrier heights and different vibration factors.

maximum. From these curves and similar curves for models with other interatomic distances, it was concluded that the barrier is about 4 kcal./mole.

In the above calculations, no account was taken of vibrational motion of the atoms; the models were rigid except for the restricted rotation of the CF₈ groups about the C-C axis. Curves Y_A to Y_D of Fig. 3 were calculated using in equation 2 the values of b_{ij} given in Table II. The value of 28×10^{-5} for the gauche F...F distance corresponds, to a very good approximation, to a potential barrier of 5.0 kcal./mole while the value 9.3 imes 10^{-5} is for a model which is nearly rigid with respect to internal rotation. The trans F...F distance is much less affected by restricted internal rotation and the values of $r_{ij} = 10.0 \times 10^{-5}$ for this distance allow for fairly large amplitudes of vibration affecting this distance. The remaining factors in model Y_A are taken from those used to represent the vibrations in trifluoromethylacetylene.9 The values in model Y_B are adapted from those found for tetrafluoroethylene.¹⁰ Model Y_C differs from model Y_A only in the magnitude of the damping factor for the trans F...F distance.

TABLE II

Values of b_{ij} Use	D FOR HE	XAFLUOR	OETHANE	MODELS
Model distance	$b_{ij} \stackrel{\rm YA}{\times} 10^5$	$^{\rm YB}_{bij} \times 10^{\rm s}$	$^{\rm VC}_{bij} \stackrel{\rm VC}{\times} 10^{\rm s}$	$b_{11} \stackrel{ m YD}{ imes} 10^5$
C-C	0	0	0	0
C-F	1.5	11.5	1.5	1.5
CF	9.0	41.9	9.0	9.0
\mathbf{F} \mathbf{F}	6.8	34.6	6.8	6.8
FF (gauche)	28.0	28 .0	28.0	9.3
FF (trans)	1.0	1.0	10.0	10.0

In curve Y_A the shelf on the fourth maximum is slightly more intense than in curve Y_5 with which it is to be compared; otherwise these curves are in good agreement. The factors used in Y_B are seen to be far too severe while Y_C is seen to be in good agreement with Y_5 . Curve Y_D is clearly not in agreement with Y_5 .

The conclusion from these and similar curves for other models in Fig. 1 is that the motion due to restricted internal rotation is much more important for the electron diffraction study than is the usual vibrational motion. So long as reasonable values of vibration factors are used (*e.g.*, those in models Y_A and Y_C), the curves are virtually the same as for models in which only the internal rotation is taken into account. Thus it seems that no damping factors are necessary for the bonded and nonbonded C-F and the short F-F distances; the final results of this investigation (Table III) are based on models in which no damping was applied to these distances.

Discussion of Results

Table III lists the values which are obtained from the various acceptable and borderline models after multiplying by the q/q_0 ratios. Also listed are the final values together with the radial distribution results (R.D.). These latter results are based on strong radial distribution peaks at 1.33,

(9) J. N. Schoolery, R. G. Shulman, W. F. Sheehan, V. Schomaker and D. M. Yost, J. Chem. Phys., 19, 364 (1951).

(40) I. J., Karle and J. Karle, *ibid.*, **18**, 957 (4950).

TABLE III	
Distances (in Å.) Obtained	FROM q/q_0 VALUES

				Мо	del				F	inal results w of accepta	ith limi bility	ts
Distance for	Р	R	S	х	Y	Z	CC	DD	Fin	al values	R.D.	
C-F	1.333	1.332	1.336	1.322	1.328	1.330	1.319	1.326	1.330	0 ± 0.015	1.33	
C-C	1.509	1.487	1.469	1.543	1.526	1.506	1.563	1.547	1.51	\pm .06		1.53^a
FF	2.146	2.142	2.156	2.144	2.150	2.160	2.151	2.160	2.15	\pm .02	2.16	
CF	2.351	2.335	2.318	2.353	2.348	2.337	2.353	2.350	2.34	\pm .03	2.35	
FF (gauche)	2.772	2.759	2.747	2.762	2.754	2.737	2.737	2.732	2.76	± .03	2.76	2.75^{a}
FF(trans)	3.507	3.492	3.491	3.495	3.497	3.480	3.490	3.486	3.49	\pm .02	3.51	3.50^{a}
∠ FCF	107.5°	107.5°	107.5°	108.5°	108.5°	108.5°	109.5°	109.5°	108°	$\pm 1.5^{\circ}$		

^a Calculated from the three prominent peaks in the R.D. curve at 1.33, 2.16 and 2.35 Å.

2.16 and 2.35 Å. and less intense (and less reliable) peaks at 2.76 and 3.51 Å.

The C-C distance of 1.51 ± 0.06 Å. obtained in this investigation is intermediate between that obtained in the two previous investigations² and is believed to be more reliable than either of the previous results. The bonded C-F distance is more accurately determined than the C-C distance and is given here as 1.330 ± 0.015 Å. which is somewhat shorter than that reported in the previous investigations. Finally, the FCF angle is essentially in agreement with the previous results.

The results of this investigation do not make it possible to say with certainty whether the C-C distance in hexafluoroethane is the same as that in ethane; it is probable, however, that this distance is very nearly the same in the two compounds. The structure of the CF3 group in C2F6 may be compared with the structure of this group in several other compounds. In the case of CHF3, a recent electron diffraction investigation¹¹ by the rotating sector method gave C-F = 1.334 ± 0.005 Å. and \angle FCF = $108^{\circ}30' \pm 30'$ which agree well

(11) L. O. Brockway, private communication.

with microwave results¹² of 1.332 Å. and 108°48', respectively. A microwave investigation¹³ of CF₃-Br yielded C-F = 1.33 ± 0.015 Å. with \angle FCF assumed to be 108 \pm 1°. In the case of F₃CC= CCF₃, an electron diffraction study¹⁴ indicated a C-F distance of 1.340 ± 0.020 Å, with \angle FCF = 107.5 \pm 1°. An investigation of the structure of HC≡CCF₈ by a combination of electron diffraction and microwave methods⁹ gave C-F = 1.335 ± 0.01 Å, and \angle FCF = $107.5 \pm 1^{\circ}$. It is noteworthy that in all these cases the C-F distance is very nearly the same and that the FCF angle is less than the tetrahedral value.

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LAFAYETTE, INDIANA

[CONTRIBUTION FROM THE GEORGE HERBERT JONES LABORATORY OF THE UNIVERSITY OF CHICAGO

Tracer Studies on the Decomposition of Ozone in Water

BY OTTO L. FORCHHEIMER AND H. TAUBE

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The direct exchange of O_3 with water in acid solution is very slow; however, exchange does take place to a limited extent when decomposition occurs. The exchange induced on decomposition is inhibited by Cl⁻, HOAc and HNO₃ (at high con-centration), but is the same in dilute HClO₄, HNO₃ or H₂SO₄ solution, and is the same for the hydrogen peroxide induced and the spontaneous decomposition. The extent of exchange increases as O₃ concentration decreases, to a value equivalent to the exchange of $\frac{1}{6}$ of the oxygen of the ozone decomposed. These results, in particular the extent of exchange, demonstrate hydroxyl radical as the exchange and decomposition active intermediate for the non-inhibited reactions. In alkaline solution, the exchange of ozonized oxygen and water under some conditions is greater than can be accounted for by the exchange of all the ozone decomposed; ozone catalyzes or induces the exchange of O_2 with water in alkali.

The hydroxyl radical has been proposed as an intermediate in a great variety of reactions in water solution.¹ While it is likely that this species is actually involved in many of the systems, in no case has proof been advanced that the intermediate carrying the bulk of the reaction is really the hydroxyl radical. The ubiquitous nature of the radical derives from the simple chemistry relating it to water, hydrogen peroxide and ozone, the difficulty of characterizing it from its high reactivity. It

(1) N. Uri, Chem. Revs., 50, 375 (1952).

apparently reacts with a wide variety of substances, whether reagents or impurities in them, and even with rather inert reducing agents such as Cl- and HOAc.² The general ambiguity about mecha-nisms involving it centers around the question of whether a particular powerful oxidizing intermediate under study is the hydroxyl radical, or an intermediate generated by the reaction of hydroxyl radical with some substance in the solution. Thus in the work on the decomposition of ozone induced

(2) H. Taube and W. C. Bray, THIS JOURNAL, 62, 3357 (1940).